

Supplementary Information

Pioneering dielectric materials of Sn-doped $\text{Nb}_{0.025}\text{Ti}_{0.975}\text{O}_2$
ceramics with excellent temperature and humidity stability for
advanced ceramic capacitors

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Table 1 Lattice parameters, Raman shifts of E_g and A_{1g} modes, and bond lengths for 1%Sn–NTO, 2.5%Sn–NTO, and 5%Sn–NTO ceramics.

Sample condition	1%Sn–NTO	2.5%Sn–NTO	5%Sn–NTO
$a = b$ (Å)	4.605(9)	4.608(7)	4.611(9)
c (Å)	2.965(6)	2.969(2)	2.973(9)
E_g (cm ⁻¹)	438.7	438.0	436.5
A_{1g} (cm ⁻¹)	606.1	606.6	607.2
Bond length (Å)	$\mathbf{A} = \text{Ta, Sn, Ti}$		
$\mathbf{A}_{(0,0,0)}-\mathbf{O}_{(0.19480, -0.19480, 0.50000)}$	1.952(0)	1.953(0)	1.956(0)
$\mathbf{A}_{(0,0,0)}-\mathbf{O}_{(0.30520, 0.30520, 0.00000)}$	1.988(0)	1.989(0)	1.991(0)
$\mathbf{A}_{(0,0,0)}-\mathbf{O}_{(0.30520, -0.69480, 0.00000)}$	3.495(1)	3.497(1)	3.500(1)
$\mathbf{A}_{(0,0,0)}-\mathbf{A}_{(0, 0, 1)}$	2.966(1)	2.969(1)	2.974(1)

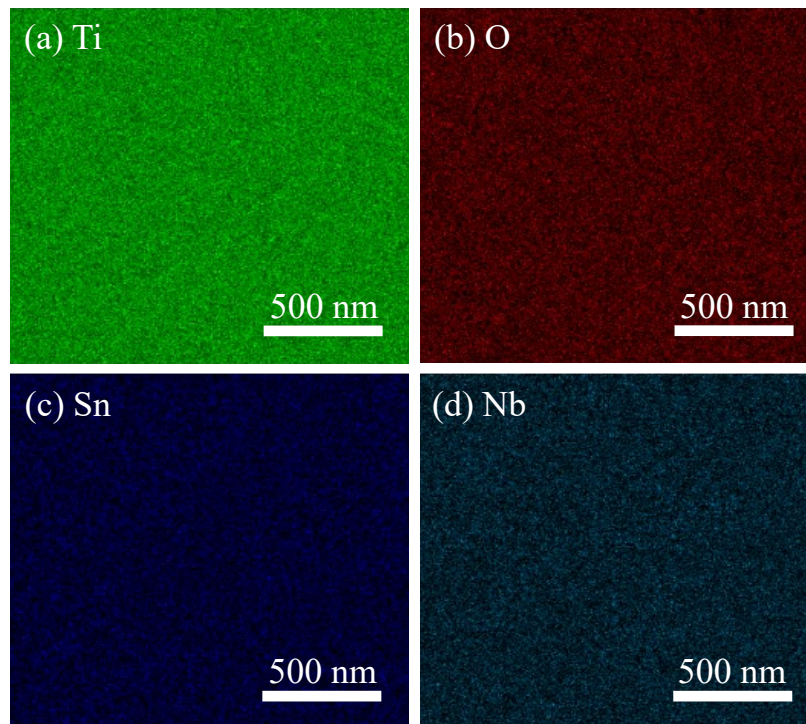


Fig. S1 SEM mapping of (a) Ti, (b) O, (c) Sn, and (d) Nb for 5%Sn–NTO ceramic.

Fig. S1 presents mapping images of all elements in 5%Sn–NTO ceramic sintered at 1200 °C for 3h. Generally, a second phase was observed in specific regions, such as grain boundaries, which were indicated by lighter areas in the elemental mapping. Notably, a homogeneous distribution of Sn, Nb, Ti, and O elements was detected along both grains and grain boundaries on the surface morphology of the 5% Sn–NTO ceramic. There was no accumulation of several phases in specific regions, indicating the absence of secondary phases. The result is similar to other works in co-doped rutile TiO₂ ceramics [1, 2].

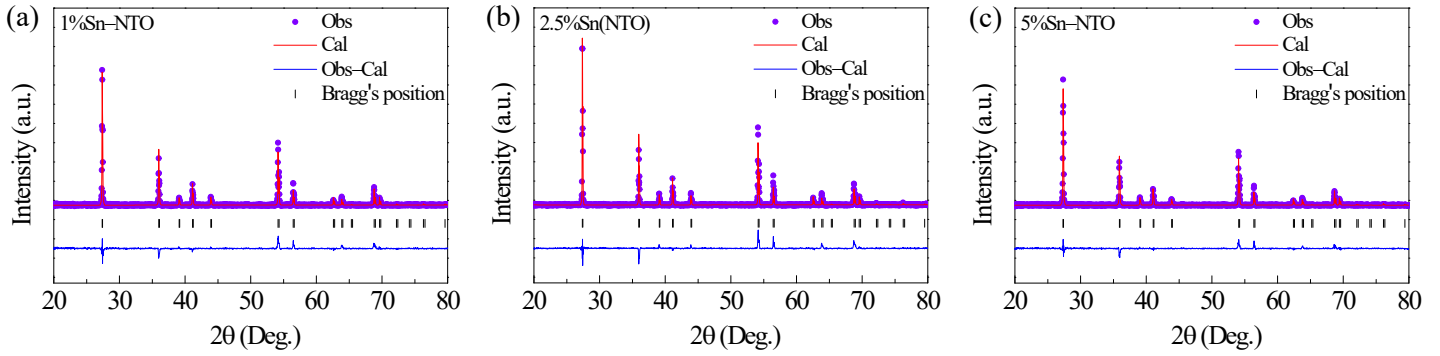


Fig. S2 Rietveld profile fitting for (a) 1%Sn-NTO, (b) 2.5%Sn-NTO, and (c) 5%Sn-NTO ceramics.

Fig. S2 illustrates the Rietveld refinement fitting for the 1%Sn-NTO, 2.5% Sn-NTO and 5% Sn-NTO ceramics, respectively, using X'pert High Score Plus program. A rutile TiO_2 phase was observed in all samples. Lattice parameters (a and c) and bond lengths (A-O and A-A , where $\text{A} = \text{Ta}$, Sn , Ti) were calculated and summarized in Table 1. These values increased with higher Sn^{4+} concentrations. The results were attributed to the effect of Nb^{5+} and Sn^{4+} radii, where $r_6(\text{Nb}^{4+}) = 64.0$ pm and $r_6(\text{Sn}^{4+}) = 69.0$ pm, which are larger than the Ti^{4+} host ions ($r_6(\text{Ti}^{4+}) = 60.5$ pm) by approximately 5.8% and 14.0%, respectively [2, 3]. The variance in dopant radii is associated with the expansion of lattice parameters and bond lengths, influenced by the presence of Sn^{4+} ions. Importantly, the absence of a second phase in the 1–5%Sn-NTO ceramics indicated that both dopants completely replaced Ti^{4+} sites [2].

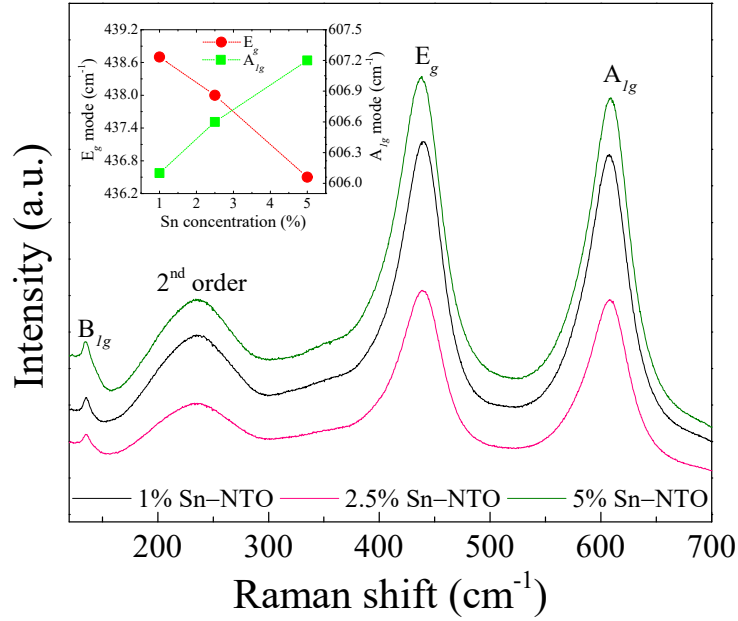


Fig. S3 Raman spectra of Sn–NTO ceramics sintered at 1200 °C for 3h. The inset shows Raman shift of E_g and A_{1g} modes of Sn–NTO ceramics as a function of Sn⁴⁺ concentrations.

Fig. S3 shows Raman peaks of rutile TiO₂ include B_{1g}, E_g and A_{1g} modes, as well as the multi-phonon peak of a second-order (2nd order) effect for Sn–NTO ceramics [4, 5]. In the inset of Fig. S3, the Raman peaks of E_g were revealed to shift toward the low energy side in the range from 439 to 437 cm⁻¹ with increasing Sn⁴⁺ concentrations. The result can be attributed to the lattice distortion and the movement of oxygen along c-axis [4]. In contrast, the A_{1g} mode exhibited a slight shift to higher frequency side from 601 to 607 cm⁻¹ with increasing Sn⁴⁺ concentrations, as a result of the influence of the Ti–O stretch modes [6]. Both E_g and A_{1g} peak shift values were determined using the Lorentz model, as listed in Table 1.

Reference

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